



AP04

Gate Protected

Preliminary

8 Channel MOSFET Array Monolithic P-Channel Enhancement Mode

Ordering Information

BV _{DSS} / BV _{DGS} (min)	R _{DS(ON)} (max)	I _{D(ON)} (min)	I _{DSS} ** @ V _{DS} = -100V Max	I _{DSS} ** @ V _{DS} = -250V Max	Order Number / Package		
					18-Lead Plastic DIP	Plastic SOW-20*	Die†
-160V	700Ω	-15mA	-1.5nA	—	AP0416NA	AP0416WG	AP0416ND
-200V	600Ω	-15mA	—	—	AP0420NA	—	AP0420ND
-300V	600Ω	-15mA	—	—	AP0430NA	—	AP0430ND
-320V	700Ω	-15mA	—	-1.5nA	AP0432NA	AP0432WG	AP0432ND
-400V	700Ω	-15mA	—	—	AP0440NA	AP0440WG	AP0440ND

* Same as SO-20 with 300 mil wide body.
 ** Average current per channel, measured with all eight channels connected in parallel.
 † MIL visual screening available

Features

- ESD gate protection
- Low drain to source leakage for AP0416 and AP0432
- 160-volt to 400-volt capability
- Interfaces directly to CMOS logic
- 8 Independent channels
- Low crosstalk between channels
- Low power dissipation
- Pin compatible with industry standard driver array
- Free from secondary breakdown

Applications

- High impedance/low leakage measurements for bare board testers
- High voltage electroluminescent panel drivers
- High voltage electrostatic array drivers
- General multi-channel driver array

Absolute Maximum Ratings

Drain-to-Source Voltage	BV _{DSS}
Drain-to-Gate Voltage	BV _{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C
Channel-to-Channel Crosstalk	10mV/V

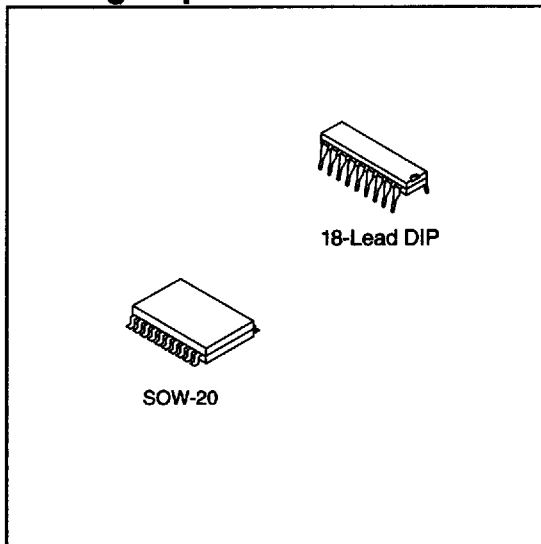
* Distance of 1.6 mm from case for 10 seconds.

General Description

The Supertex AP04 series of high voltage arrays is a ruggedized ESD gate protected version of the Supertex AP01 series. These multichannel arrays meet the EIA ESD standard of 2000V, 100pF capacitor in series with a 1.5KΩ resistor. They are designed to provide interface between CMOS logic and loads requiring high voltages and intermediate currents. Each circuit consists of eight channels in a common-source configuration with open drains. This design minimizes the number of package leads needed.

The AP0416 and AP0432 are ideally suited for low leakage/high impedance measurement, providing excellent accuracy and resolution for automatic test equipment.

Package Options



Thermal Characteristics

Package	I _D (continuous)*	I _D (pulsed)*	Power Dissipation @ T _C =25°C	θ _{JA} °C/W	θ _{JC} °C/W	I _{DR}	I _{DRM} *
18 lead plastic	-15mA	-40mA	1.5W	135	83	-15mA	-40mA
SOW -20	-15mA	-40mA	1.4W	110	89	-15mA	-40mA

* I_D (continuous) is limited by max rated T_J

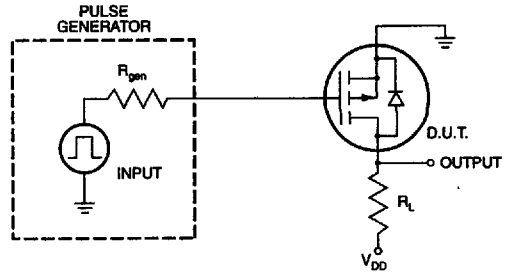
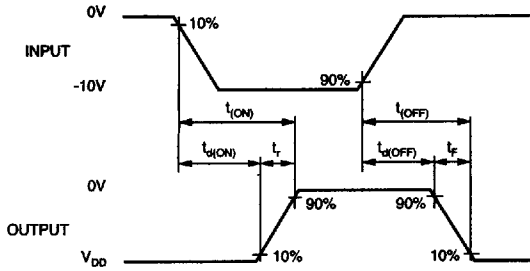
Electrical Characteristics (@ 25°C unless otherwise specified)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions	
BV _{DSS}	Drain-to-Source Breakdown Voltage	AP0416	-160			V	I _D = -100µA, V _{GS} = 0V	
		AP0420	-200					
		AP0430	-300					
		AP0432	-320					
		AP0440	-400					
V _{GS(th)}	Gate Threshold Voltage		-2		-5	V	V _{GS} = V _{DS} , I _D = -1mA	
ΔV _{GS(th)}	Change in V _{GS(th)} with Temperature			-3.5		mV/°C	V _{GS} = V _{DS} , I _D = -1mA	
I _{GSS}	Gate Body Leakage	AP0420				nA	V _{GS} = ±20V, V _{DS} = 0V (3)	
		AP0430			-10			
		AP0440						
		AP0416			-1			
		AP0432						
I _{DSS}	Zero Gate Voltage Drain Current	AP0420			-1	µA	V _{GS} = 0, V _{DS} = Max Rating (3)	
		AP0430			-1	mA	V _{GS} = 0, V _{DS} = 0.8 Max Rating T _A = 125°C (3)	
		AP0440						
		AP0416			-1.5	nA	V _{GS} = 0V, V _{DS} = -100V (3)	
						-3	µA	V _{GS} = 0V, V _{DS} = 0.8 Max Rating T _A = 125°C (3)
		AP0432				-1.5	nA	V _{GS} = 0V, V _{DS} = -250V (3)
					-3	µA	V _{GS} = 0V, V _{DS} = 0.8 Max Rating T _A = 125°C (3)	
I _{D(ON)}	ON-State Drain Current		-15			mA	V _{GS} = -10V, V _{DS} = -25V	
R _{DS(ON)}	Static Drain-to-Source	AP0420			600	Ω	V _{GS} = -10V, I _D = -10mA	
		AP0430						
	ON-State Resistance	AP0416				700	Ω	V _{GS} = -10V, I _D = -10mA
		AP0432						
		AP0440						
ΔR _{DS(ON)}	Change in R _{DS(ON)} with Temperature			0.8		%/°C	V _{GS} = -10V, I _D = -10mA	
G _{FS}	Forward Transconductance		3.0	5.0		m \bar{S}	V _{DS} = -25V, I _D = -5mA	
C _{ISS}	Input Capacitance			8.0	12.0	pF	V _{DS} = -25V, V _{GS} = 0V f = 1 MHz	
C _{OSS}	Common Source Output Capacitance			5.0	8.0			
C _{RSS}	Reverse Transfer Capacitance			1.6	3.2			
t _{d(ON)}	Turn-ON Delay Time			5.0		ns	V _{DD} = -25V, I _D = -10mA, R _{GEN} = 25Ω	
t _r	Rise Time			5.0				
t _{d(OFF)}	Turn-OFF Delay Time			8.0				
t _f	Fall Time			5.0				
V _{SD}	Diode Forward Voltage Drop				-1.5			V

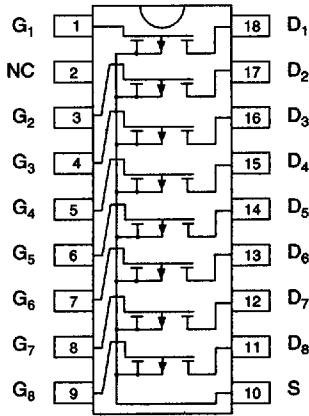
Notes:

- All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300µs pulse, 2% duty cycle.)
- All A.C. parameters sample tested.
- Average current per channel, measured with all 8 channels connected in parallel.

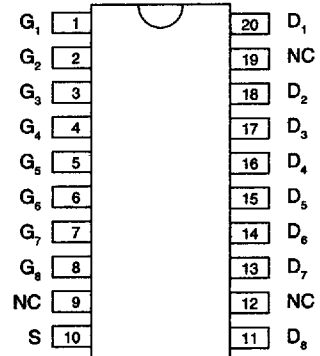
Switching Waveforms and Test Circuit



Pin Configuration and Schematic



top view
18-pin DIP



top view
SOW - 20